Se	earch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/674,623	BAYLIS ET AL.	
Examiner	Art Unit	
Ernesto Garcia	3679	

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Class	Subclass	Date	Examiner
403	270,339,3 40,409.1	11/22/2005	EG
123	184.21	11/22/2005	EG
123	184.61	11/22/2005	EG
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Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
264/ (Consulted Patrick Butler); 123/184.22-184.60 (cursory)	11/22/2005	EG
Text Search (see East attachment)	11/23/2005	EG